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DOT MATRIX LED DISPLAY(1.2Inch)

LMD6711/2BSE-XX

DATA SHEET

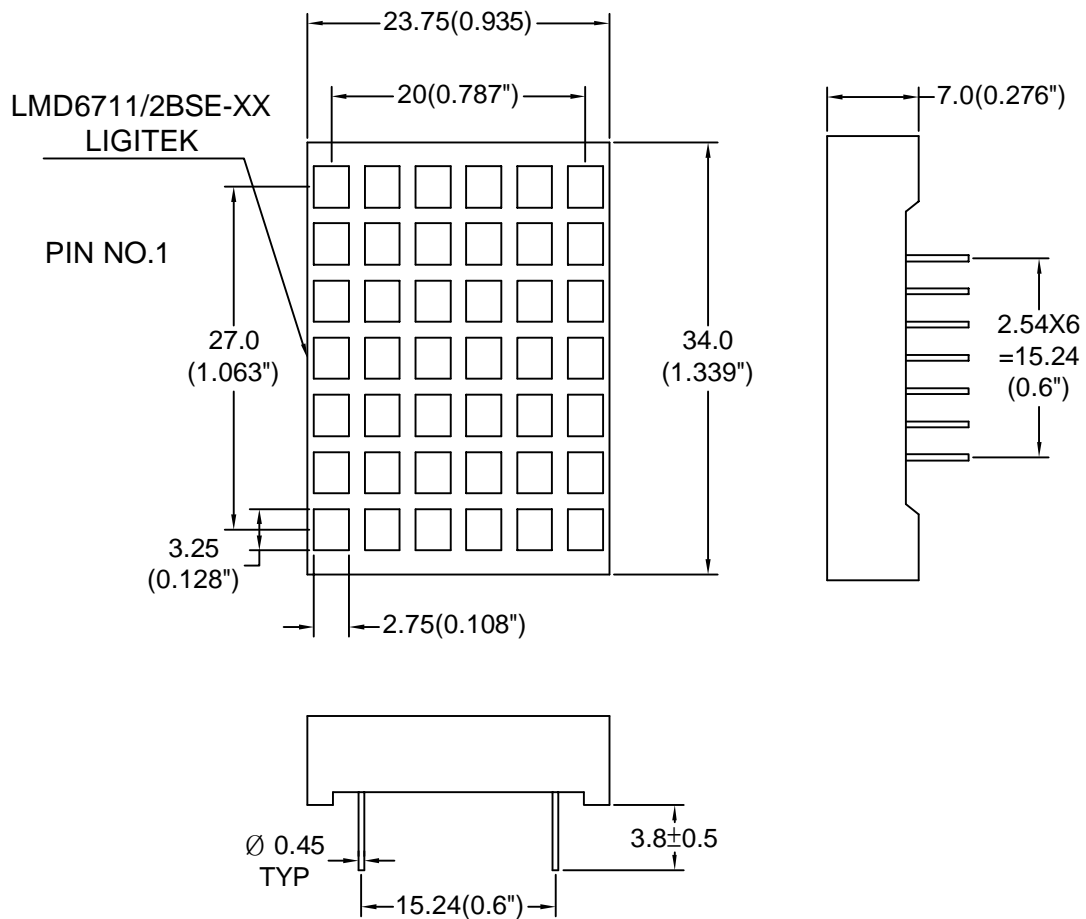
DOC. NO : QW0905-LMD6711/2BSE-XX

REV. : D

DATE : 20 - Jan. - 2006



Package Dimensions

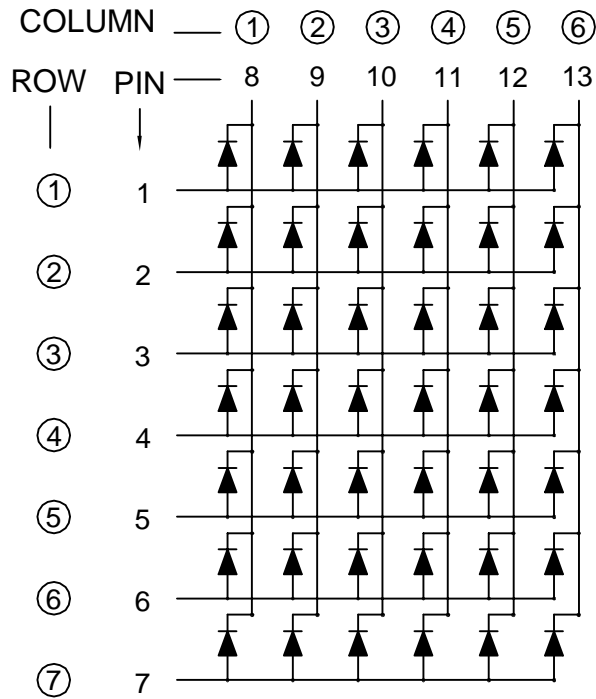


Note : 1.All dimension are in millimeters and (Inch) tolerance is ± 0.25 mm unless otherwise noted.
2.Specifications are subject to change without notice.

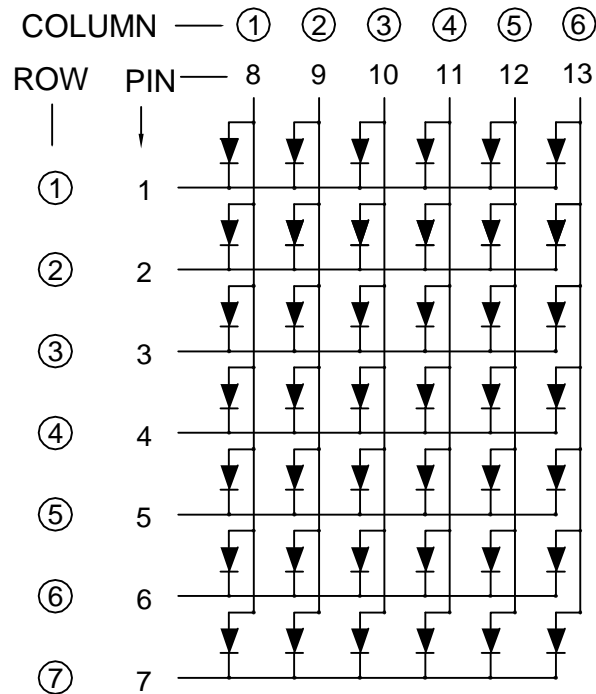


Internal Circuit Diagram

LMD6711BSE-XX



LMD6712BSE-XX





Electrical Connection

PIN NO.	LMD6711BSE-XX	PIN NO.	LMD6712BSE-XX
1.	Anode Row 1	1.	Cathode Row 1
2.	Anode Row 2	2.	Cathode Row 2
3.	Anode Row 3	3.	Cathode Row 3
4.	Anode Row 4	4.	Cathode Row 4
5.	Anode Row 5	5.	Cathode Row 5
6.	Anode Row 6	6.	Cathode Row 6
7.	Anode Row 7	7.	Cathode Row 7
8.	Cathode Column 1	8.	Anode Column 1
9.	Cathode Column 2	9.	Anode Column 2
10.	Cathode Column 3	10.	Anode Column 3
11.	Cathode Column 4	11.	Anode Column 4
12.	Cathode Column 5	12.	Anode Column 5
13.	Cathode Column 6	13.	Anode Column 6
14.	No Pin	14.	No Pin



Absolute Maximum Ratings at Ta=25 °C

Parameter	Symbol	Ratings	UNIT
		SE	
Forward Current Per Chip	IF	20	mA
Peak Forward Current Per Chip (Duty 1/10,0.1ms Pulse Width)	IFP	80	mA
Power Dissipation Per Chip	PD	80	mW
Reverse Current Per Any Chip	Ir	10	μA
Operating Temperature	Topr	-25 ~ +85	°C
Storage Temperature	Tstg	-25 ~ +85	°C

Solder Temperature 1/16 Inch Below Seating Plane For 3 Seconds At 260 °C

Part Selection And Application Information(Ratings at 25°C)

PART NO	CHIP		common cathode or anode	λ P (nm)	Δ λ (nm)	Electrical					IV-M
	Material	Emitted				Vf(v)			Iv(mcd)		
						Min.	Typ.	Max.	Min.	Typ.	
LMD6711BSE-XX	GaAsP/GaP	Orange	Common Cathode	610	45	1.7	2.1	2.6	2.35	4.0	2:1
LMD6712BSE-XX			Common Anode								

Note : 1.The forward voltage data did not including ±0.1V testing tolerance.
2. The luminous intensity data did not including ±15% testing tolerance.



Test Condition For Each Parameter

Parameter	Symbol	Unit	Test Condition
Forward Voltage Per Chip	Vf	volt	If=20mA
Luminous Intensity Per Chip	Iv	mcd	If=10mA
Peak Wavelength	λ_p	nm	If=20mA
Spectral Line Half-Width	$\Delta \lambda$	nm	If=20mA
Reverse Current Any Chip	Ir	μA	Vr=5V
Luminous Intensity Matching Ratio	IV-M		

器具規格

1. 素子規格

- (1)表示素子 ----LED
(2)表示色 ----橘紅色
(3)輝度 ----250cd (周圍照度 0 Lux 時)
(4)壽命 ----輝度半減期 50.000 Hr
(5)光亮度 ----無規定 (1dot 內光亮平均)

2. 表示器規格

- (1)輝度 ----表示器內及同一 LOT內之表示器,輝度無規定.
(鄰接DOT之輝度差 50% 以下)
(2)光亮度 ----無規定



Typical Electro-Optical Characteristics Curve

SE CHIP

Fig.1 Forward current vs. Forward Voltage

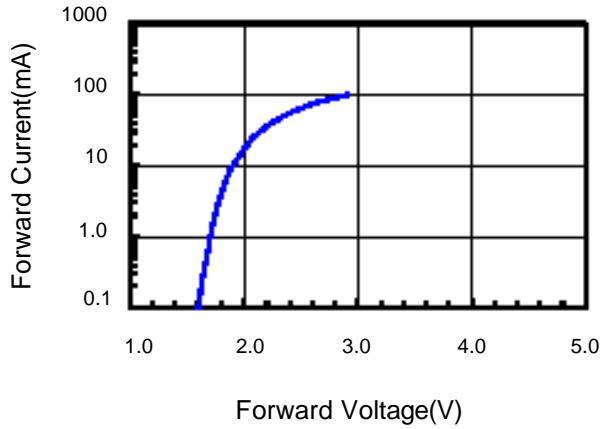


Fig.2 Relative Intensity vs. Forward Current

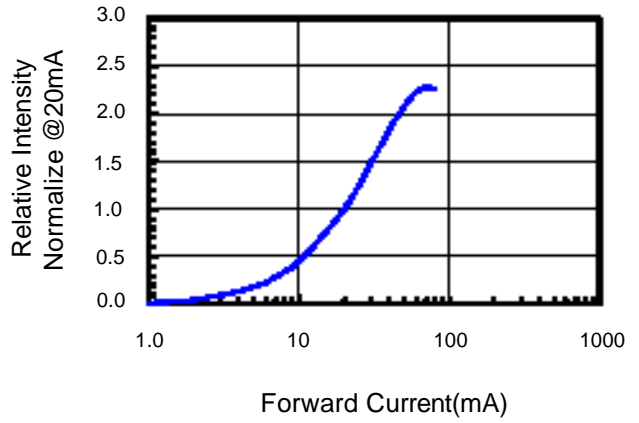


Fig.3 Forward Voltage vs. Temperature

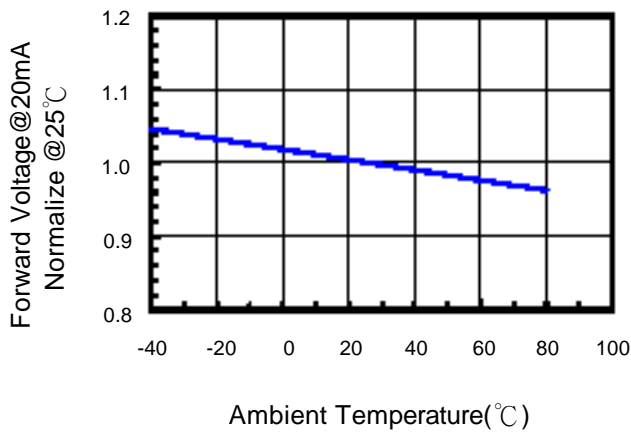


Fig.4 Relative Intensity vs. Temperature

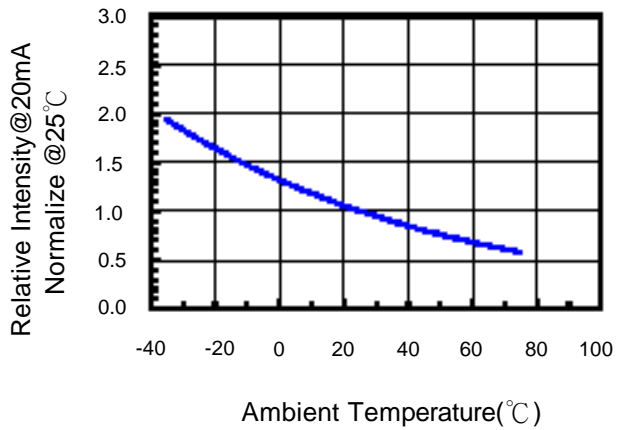
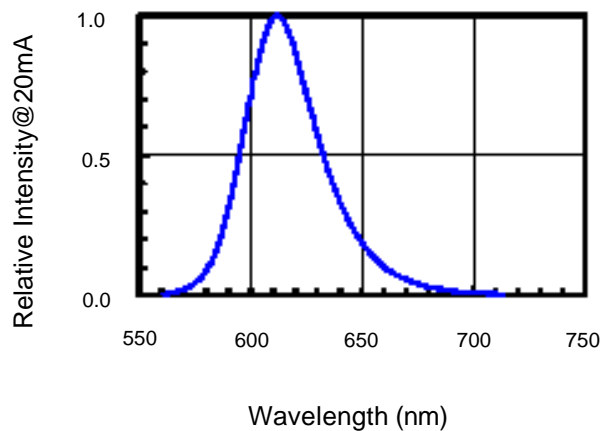


Fig.5 Relative Intensity vs. Wavelength



**Reliability Test:**

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=10mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and thermal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 °C ±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 °C ±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 °C ±5°C 2.RH=90%~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 °C ±5°C & -40 °C ±5°C (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 °C ±5°C 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 °C ±5°C 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2